

# A A Allerman

## List of Publications by Year in descending order

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39  
papers

2,702  
citations

257450

24  
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434195

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g-index

39  
all docs

39  
docs citations

39  
times ranked

1746  
citing authors

#	ARTICLE	IF	CITATIONS
1	InGaAsN solar cells with 1.0 eV band gap, lattice matched to GaAs. Applied Physics Letters, 1999, 74, 729-731.	3.3	511
2	Effect of threading dislocations on the Bragg peakwidths of GaN, AlGaIn, and AlN heterolayers. Applied Physics Letters, 2005, 86, 241904.	3.3	250
3	Junction and carrier temperature measurements in deep-ultraviolet light-emitting diodes using three different methods. Applied Physics Letters, 2005, 86, 031907.	3.3	182
4	Band structure of In <sub>x</sub> Ga <sub>1-x</sub> As <sub>1-y</sub> N <sub>y</sub> alloys and effects of pressure. Physical Review B, 1999, 60, 4430-4433.	3.2	172
5	Time-resolved photoluminescence studies of In <sub>x</sub> Ga <sub>1-x</sub> As <sub>1-y</sub> N <sub>y</sub> . Applied Physics Letters, 2000, 76, 188-190.	3.3	162
6	Room-temperature direct current operation of 290 nm light-emitting diodes with milliwatt power levels. Applied Physics Letters, 2004, 84, 3394-3396.	3.3	155
7	Minority carrier diffusion, defects, and localization in InGaAsN, with 2% nitrogen. Applied Physics Letters, 2000, 77, 400-402.	3.3	153
8	Strain relaxation in AlGaIn multilayer structures by inclined dislocations. Journal of Applied Physics, 2009, 105, .	2.5	133
9	Improved brightness of 380 nm GaN light emitting diodes through intentional delay of the nucleation island coalescence. Applied Physics Letters, 2002, 81, 1940-1942.	3.3	126
10	Review "Ultra-Wide-Bandgap AlGaIn Power Electronic Devices. ECS Journal of Solid State Science and Technology, 2017, 6, Q3061-Q3066.	1.8	104
11	Minority carrier diffusion and defects in InGaAsN grown by molecular beam epitaxy. Applied Physics Letters, 2002, 80, 1379-1381.	3.3	89
12	Deep levels in p-type InGaAsN lattice matched to GaAs. Applied Physics Letters, 1999, 74, 2830-2832.	3.3	83
13	InAsSb-based mid-infrared lasers (3.8-3.9 μm) and light-emitting diodes with AlAsSb claddings and semimetal electron injection, grown by metalorganic chemical vapor deposition. Applied Physics Letters, 1996, 69, 465-467.	3.3	74
14	Laser gain and threshold properties in compressive-strained and lattice-matched GaInNAs/GaAs quantum wells. Applied Physics Letters, 1999, 75, 2891-2893.	3.3	67
15	Relaxation of compressively-strained AlGaIn by inclined threading dislocations. Applied Physics Letters, 2005, 87, 121112.	3.3	63
16	Hydrogen configurations, formation energies, and migration barriers in GaN. Journal of Applied Physics, 2003, 94, 2311-2318.	2.5	46
17	Midinfrared lasers and light-emitting diodes with InAsSb/InAsP strained-layer superlattice active regions. Applied Physics Letters, 1997, 70, 3188-3190.	3.3	45
18	Minimizing threading dislocations by redirection during cantilever epitaxial growth of GaN. Applied Physics Letters, 2002, 81, 2758-2760.	3.3	44

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19	Deep levels and their impact on generation current in Sn-doped InGaAsN. Journal of Applied Physics, 2001, 90, 3405-3408.	2.5	40
20	In situ measurements of GaN nucleation layer decomposition. Applied Physics Letters, 2003, 82, 1170-1172.	3.3	40
21	Deep-level defects in InGaAsN grown by molecular-beam epitaxy. Applied Physics Letters, 2002, 80, 4777-4779.	3.3	39
22	The influence of Al composition on point defect incorporation in AlGaIn. Applied Physics Letters, 2012, 100, 043509.	3.3	38
23	High slope efficiency, cascaded midinfrared lasers with type I InAsSb quantum wells. Applied Physics Letters, 1998, 72, 2093-2095.	3.3	29
24	Photoluminescence-linewidth-derived reduced exciton mass for In <sub>y</sub> Ga <sub>1-y</sub> As <sub>1-x</sub> N <sub>x</sub> alloys. Physical Review B, 2000, 62, 7144-7149.	3.2	27
25	The metalorganic chemical vapor deposition growth of AlAsSb and InAsSb/InAs using novel source materials for Infrared Emitters. Journal of Electronic Materials, 1997, 26, 903-909.	2.2	15
26	The growth of InAsSb/InAsP strained-layer superlattices for use in infrared emitters. Journal of Electronic Materials, 1997, 26, 1225-1230.	2.2	8
27	Junction Temperature Measurements in Deep-UV Light-Emitting Diodes. Materials Research Society Symposia Proceedings, 2004, 831, 299.	0.1	2
28	Advances in AlGaIn-based Deep UV LEDs. Materials Research Society Symposia Proceedings, 2004, 831, 67.	0.1	2
29	The Role of Nitrogen-Induced Localization and Defects in InGaAsN (? 2% N): Comparison of InGaAsN Grown by Molecular Beam Epitaxy and Metal-Organic Chemical Vapor Deposition. Materials Research Society Symposia Proceedings, 2001, 692, 1.	0.1	1
30	Cantilever Epitaxy of GaN on Sapphire: Further Reductions in Dislocation Density. Materials Research Society Symposia Proceedings, 2002, 743, L1.8.1.	0.1	1
31	Reduction in the Number of Mg Acceptors with Al Concentration in Al <sub>x</sub> Ga <sub>1-x</sub> N. Journal of Electronic Materials, 2015, 44, 4139-4143.	2.2	1
32	Novel Mid-Infrared Lasers with Compressively Strained InAsSb Active Regions. Materials Research Society Symposia Proceedings, 1996, 450, 23.	0.1	0
33	Preparation of AlAsSb and Mid-Infrared (3-5 μm) Lasers By Metal-Organic Chemical Vapor Deposition. Materials Research Society Symposia Proceedings, 1996, 450, 43.	0.1	0
34	Recent Progress in the Growth of Mid-ir Emitters by Metalorganic Chemical Vapor Deposition. Materials Research Society Symposia Proceedings, 1997, 484, 19.	0.1	0
35	Time-Resolved Photoluminescence Studies of In <sub>x</sub> Ga <sub>1-x</sub> As <sub>1-y</sub> N <sub>y</sub> . Materials Research Society Symposia Proceedings, 1999, 607, 153.	0.1	0
36	Characterization of Dark-Block Defects in Cantilever Epitaxial GaN on Sapphire. Materials Research Society Symposia Proceedings, 2002, 743, L3.15.1.	0.1	0

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37	Characterization of Minority-Carrier Hole Transport in Nitride-Based Light-Emitting Diodes with Optical and Electrical Time-Resolved Techniques. Materials Research Society Symposia Proceedings, 2004, 831, 108.	0.1	0
38	The Mg impurity in nitride alloys. , 2014, , .		0
39	Comparison of deep level spectra of MBE- and MOCVD-grown InGaAsN. Materials Research Society Symposia Proceedings, 2002, 719, 1331.	0.1	0